

**AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions and listings of claims in the application, and entry of this listing of claims is respectfully requested:

**Listing of Claims**

- 
1. (Currently Amended): A method for testing the crimped state of a test terminal on the  
2 basis of a waveform of [[the]] characteristic values obtained in the process of crimping the test  
3 terminal on a core of an electric wire, comprising the steps of:  
4       acquiring a reference waveform from [[the]] a characteristic waveform when [[the]] a first  
5       terminal has been crimped normally, and dividing the reference waveform into first plural reference  
6       waveform segments, the reference waveform showing changes in load corresponding to time elapsed  
7       when the first terminal is crimped normally, each of the first plural reference waveform segments  
8       corresponding to a segment of time elapsed when the first terminal is crimped normally;  
9       dividing the a characteristic waveform obtained when [[a]] the test terminal to be tested is  
10      crimped on the electric wire into [[a]] second plural waveform segments corresponding to those of  
11      the reference waveform; and  
12      deciding whether or not the crimped state of the test terminal is good on the basis of the first  
13      reference waveform segments of the reference waveform and the second waveform segments of the  
14      characteristic waveform obtained when the test terminal is crimped.

U.S. Patent Application Serial No. 10/079,401

Response dated October 15, 2003

**Reply to OA of July 16, 2003**

Page 5 of 14

2. (Currently Amended): The [[A]] method of testing the crimped state of a test terminal according to claim 1, wherein singular points of the reference waveform are previously acquired on the basis of increments of the reference waveform; and said first reference waveform segments contain said singular points.

3. (Currently Amended): The [[A]] method of testing the crimped state of a test terminal according to claim 1, wherein singular points of the reference waveform are previously acquired on the basis of increments of the reference waveform; and said first reference waveform segments are located between the singular points.

4. (Currently Amended): A method for testing the crimped state of a test terminal on the basis of a waveform of [[the]] characteristic values obtained in the process of crimping the test terminal on a core of an electric wire, comprising the steps of:

acquiring a reference waveform from [[the]] a characteristic waveform when [[the]] a first terminal has been crimped normally, the reference waveform showing changes in load corresponding to time elapsed when the first terminal is crimped normally;

acquiring singular points of the reference waveform on the basis of [[the]] increments thereof, the increments corresponding at least to a maximum change in load per unit time and a zero change in load per unit time;

acquiring second first reference waveform segments which are segments containing the

11 singular points;

12 acquiring second waveform segments containing [[the]] points corresponding to said singular  
13 points in the ~~characteristic~~ waveform obtained when the test terminal ~~to be tested~~ has been crimped  
14 on the electric wire; and

15 deciding whether or not the crimped state of the test terminal is good on the basis of said  
16 ~~second~~ first reference waveform segments and said second waveform segments.

*(f5  
f1.)  
C2)*  
5. (Currently Amended): The [[A]] method of testing the crimped state of a test terminal  
according to claim 2, wherein said singular points are points where the ~~increment~~ increments of said  
reference waveform [[is]] correspond to at least one selected from among a maximum change in load  
per unit time [[or]] and a zero change in load per unit time.

1 6. (Currently Amended): A method for testing the crimped state of a test terminal on the  
2 basis of a waveform of [[the]] characteristic values obtained in the process of crimping the test  
3 terminal on a core of an electric wire, comprising the steps of:

4 acquiring a reference waveform from [[the]] a characteristic waveform when [[the]] a first  
5 terminal has been crimped normally, and acquiring reference characteristic values at regular intervals  
6 of the reference waveform, the reference waveform showing changes in load corresponding to time  
7 elapsed when the first terminal is crimped normally;

8 acquiring [[the]] characteristic values of the ~~characteristic~~ waveform obtained when the test

U.S. Patent Application Serial No. 10/079,401  
Response dated October 15, 2003  
Reply to OA of July 16, 2003  
Page 7 of 14

9 terminal to be tested has been crimped on the electric wire, at said regular intervals; and  
10 deciding whether or not the crimped state of the test terminal is good on the basis of said  
11 reference characteristic values and the characteristic values of the waveform obtained when the test  
12 terminal has been crimped.

1 7. (Currently Amended): The [[A]] method of testing the crimped state of a test terminal  
2 according to claim 2, wherein said electric wire has a coating for coating said core,  
3 said test terminal has caulking legs for caulking said core,  
4 a first poorness waveform is acquired from the waveform obtained when the test terminal is  
5 crimped when said caulking caulking legs caulk said coating as well as said core, and  
6 a first singular point of said singular points is acquired from said reference waveform and  
7 said first poorness waveform.

1 8. (Currently Amended): The [[A]] method of testing the crimped state of a test terminal  
2 according to claim 7, wherein said first singular point is defined by a point where [[the]] a  
3 characteristic value of said first poorness waveform exceeds that of said reference waveform as the  
4 time of the crimping of the test terminal a crimping operation elapses.

1 9. (Currently Amended): The [[A]] method of testing the crimped state of a test terminal  
2 according to claim 2, wherein

U.S. Patent Application Serial No. 10/079,401  
Response dated October 15, 2003  
Reply to OA of July 16, 2003  
Page 8 of 14

3           said core is composed of a plurality of conductors tied up in a bundle;

4           said test terminal has caulking legs for caulking said core;

5           a second poorness waveform is acquired from the characteristic waveform obtained when

6           the test terminal is crimped when said caulking legs caulk conductors whose number is smaller than  
7           that when the first terminal has been normally crimped; and

8           a second singular point is acquired from said reference waveform and said second poorness

9           waveform.

1           10. (Currently Amended): The [[A]] method of testing the crimped state of a test terminal

2           according to claim 9, wherein said second singular point is defined by a point where [[the]] a

3           characteristic value of said first second poorness waveform falls below that of said reference

4           waveform as the time of the crimping of the test terminal a crimping operation elapses.

15  
16  
17  
18  
19